

Readout Electronics of DarkSHINE ECAL

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Introduction

> DarkSHINE

- > Fixed target experiment.
- > Beam: 8 GeV, 10 MHz, single electron beam from SHINE.
- > Detection object: dark photon generated by electron bremsstrahlung.
- Signal: dark photon can not be detected, resulting in the energy loss of the final state particles.



DarkSHINE ECAL

- Basic detection unit
 - > Crystal: LYSO with high light yield and good radiation hardness
 - > SiPM: S14160-3010PS with 90000 pixels and high dynamic range
- > High energy resolution
- Large dynamic range: 1 MeV 1 GeV
- > High event rate: up to 10 MHz



Requirements to the electronics

- > High energy resolution
 - > Low noise, good SNR of the front-end electronics
- High event rate: 10 MHz
 - > SiPM waveform: ~200 ns, shape to 100 ns
 - > High speed and high precision digitization
- > Large dynamic range
- ➤ 1 MeV 1 GeV: about 1000x
- SiPM calibration system

Design of the readout electronics

- Pre-amplifier > transimpedance amplifier > PZC + RCRC filter 2 channel output 总跨阻增益(Ω) 输出信号幅度 (mV) 光子蜀
- 100 4000 40 - 1600 80 - 1400 40 - 1000 4000 - 100000
- Large and small gain dual channels output : large dynamic range

High speed and high precision ADC > ADC: AD9680, 1 GSPS, 14 bit > Input driver: differential amplifier > Output to FPGA to process



LED calibration system for SiPM > LED driver: nanoseconds width and tunable light intensity



Prototype of the electronics

Pre-amplifier and 2 channels output



4 ADC card connect to a FPGA board



Test results & summary

> Pre-amplifier: low noise, good linearity > The Th-232, 2.6MeV γ spectrum

ADC performance





The energy resolution is ~ 6%.